

UNISONIC TECHNOLOGIES CO., LTD

6N40-C **Preliminary** Power MOSFET

6.0A, 400V N-CHANNEL **POWER MOSFET**

DESCRIPTION

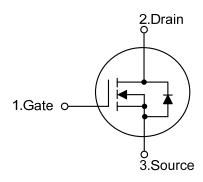
The UTC 6N40-C is an N-Channel enhancement mode power MOSFET using UTC's perfect planar stripe, DMOS technology to provide customers with superior switching performance and minimum on-state resistance. It also can withstand high energy pulse in the avalanche and commutation mode.

The UTC 6N40-C is generally used in applications, such as electronic lamp ballasts based on half bridge topology and high efficiency switched mode power supplies.

FEATURES

- * $R_{DS(ON)}$ < 1.20 @ V_{GS} =10V, I_{D} =3.0A
- * Fast switching speed
- * Improved dv/dt capability

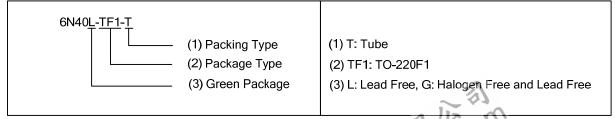
SYMBOL



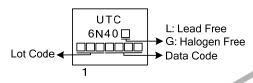
ORDERING INFORMATION

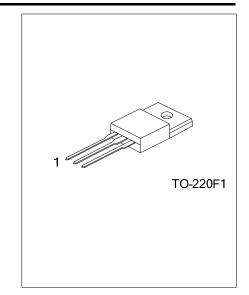
Ordering Number		Dealtons	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
6N40L-TF1-T	6N40G-TF1-T	TO-220F1	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING





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■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V _{DSS}	400	V	
Gate-Source Voltage		V _{GSS}	±30	V	
Avalanche Current (N	lote 2)	I _{AR}	6	Α	
Drain Current	Continuous	I _D	6	Α	
Drain Current	Pulsed (Note 2)	I _{DM}	24	Α	
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	150	mJ	
Peak Diode Recovery	y dv/dt (Note 4)	dv/dt	5	V/ns	
Power Dissipation		P _D	38	W	
Junction Temperature		TJ	+150	°C	
Storage Temperature		T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. L=8.3mH, I_{AS} =6.0A, V_{DD} = 50V, R_{G} =25 Ω , Starting T_{J} =25 $^{\circ}$ C
- 4. I_{SD} ≤6.0A, di/dt ≤200A/µs, V_{DD} ≤B V_{DSS} , Starting T_J =25°C

■ THERMAL RESISTANCES CHARACTERISTICS

PARAMETER	SYMBOL RATINGS		UNIT	
Junction to Ambient	θ_{JA}	62.5	°C/W	
Junction to Case	θ_{JC}	3.3	°C/W	



ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

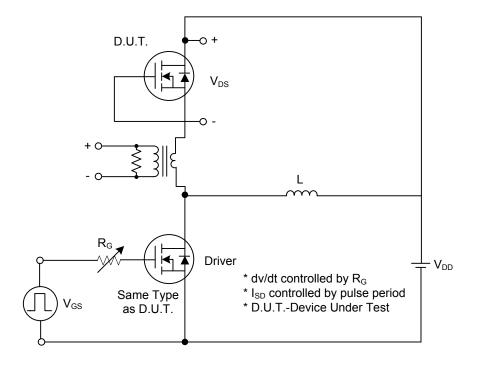
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS		l .		ı	I	l	
Drain-Source Breakdown Voltage		BV _{DSS}	V _{GS} =0V, I _D =250μA	400			V
Breakdown Voltage Temperature Coefficient		ΔBV _{DSS} /ΔT _J	I _D =250μA, Referenced to 25°C		0.54		V/°C
Drain-Source Leakage Current		I _{DSS}	V _{DS} =400V, V _{GS} =0V V _{DS} =320V, T _J =125°C			1 10	μA μA
Forwa	Forward		V _{DS} =0V ,V _{GS} =+30V			+100	nA
Gate-Source Leakage Current	Reverse	· I _{GSS}	V _{DS} =0V ,V _{GS} =-30V			-100	nA
ON CHARACTERISTICS					l.		
Gate Threshold Voltage		$V_{GS(TH)}$	V _{DS} =V _{GS} , I _D =250μA	2.0		4.0	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =3.0A			1.2	Ω	
DYNAMIC PARAMETERS							
Input Capacitance	Input Capacitance				513		pF
Output Capacitance		Coss	V _{DS} =25V,V _{GS} =0V, f=1.0MHz		75		pF
Reverse Transfer Capacitance		C _{RSS}			8		pF
SWITCHING PARAMETERS				_		_	
otal Gate Charge		Q_G	\\ _F0\\ \\ _10\\ _12\		16		nC
Gate-Source Charge		Q_{GS}	V_{DS} =50V, V_{GS} =10V, I_{D} =1.3A,		6		nC
Gate-Drain Charge		Q_{GD}	I _G =100μA (Note 1, 2)		3.2		nC
Turn-ON Delay Time	ırn-ON Delay Time				45		ns
Turn-ON Rise Time		t _{D(ON)}	V_{DD} =30V, V_{GS} =10V, I_{D} =0.5A,		57		ns
Turn-OFF Delay Time		t _{D(OFF)}	R _G =25Ω (Note 1, 2)		91		ns
urn-OFF Fall Time		t _F			36		ns
SOURCE- DRAIN DIODE RATING	S AND C	HARACTERI	STICS				
Maximum Body-Diode Continuous Current		Is				6	Α
Maximum Body-Diode Pulsed Current		I _{SM}				24	Α
Drain-Source Diode Forward Voltage		V_{SD}	I _S =6A, V _{GS} =0V			1.4	V
Body Diode Reverse Recovery Time		t _{rr}	V _{GS} =0V, I _S =6A,		230		ns
Body Diode Reverse Recovery Cha	Q _{RR}	dI _F /dt=100A/μs (Note 1)		1.4		μC	

Notes: 1. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2%.

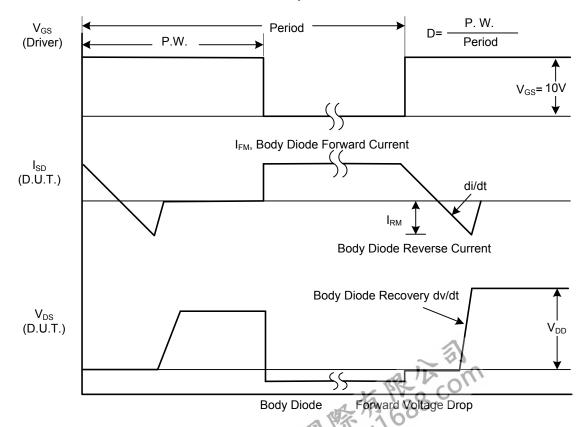
2. Essentially independent of operating temperature.



TEST CIRCUITS AND WAVEFORMS

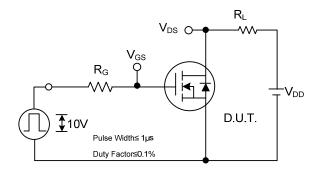


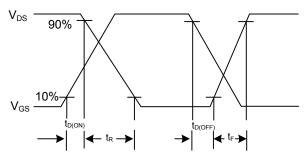
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

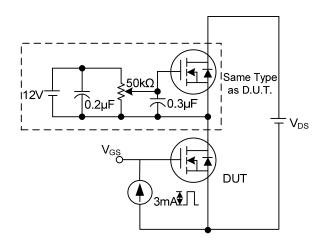
TEST CIRCUITS AND WAVEFORMS(Cont.)

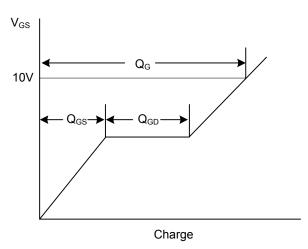




Switching Test Circuit

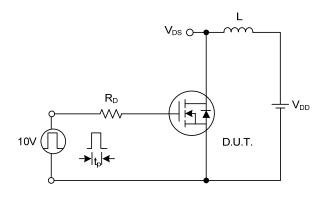
Switching Waveforms

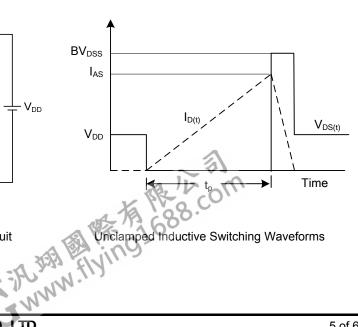




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

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